## Issue Classification



Application/Control No.	Applicant(s)/Patent Under Reexamination					
10565949	WEISS ET AL.					
Examiner	Art Unit					
Hai H Huynh	3747					

ORIGINAL					INTERNATIONAL CLASSIFICATION										
	CLASS SUBCLASS					CLAIMED						NON-CLAIMED			
123	123 325				F	0	2	D	41 / 12 (2006.01.01)						
	CD	OSS DEEL	EDENICE/	6)		F	0	2	Р	5 / 00 (2006.01.01)					
	CN	OSS REFI	-KENCE(	3)											
CLASS	SUB	CLASS (ONE	SUBCLAS	S PER BLO	CK)										
123	406.47	481	493												

NONE		Total Claims Allowed:				
(Assistant Examiner) (Date)		18				
/Hai H Huynh/ (Primary Examiner)	2-27-08 (Date)	O.G. Print Claim(s)	O.G. Print Figure			